

JA Woollam M-2000 Ellipsometer

Overview

LMACS Name	Ellipsometer (M-2000V)
Confluence Label	JA woollam-m2000-ellipsometer
Process Area	CHARACTERIZATION
Model	M-2000V
Vendor	J.A. Woollam
Team	Fenglin Liu Devin Fortier Peng Li

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System Features

- 370–1000 nm spectral range
- 1.6 nm pixel resolution; 5 nm bandwidth
- Reflection (R) intensity
- Transmission (T) intensity
- Depolarization, Mueller-matrix

Key Documents

SOP	J.A. Woollam M2000V Ellipsometer SOP
Hazard Assessment	J.A. Woollam M2000V Ellipsometer HA

Related Documents

- [JA Woollam M-2000 Ellipsometer](#) (Equipment)
 - [equipment](#)
 - [characterization](#)
 - [requires-update](#)
 - [vase-m2000-ellipsometer](#)
 - [materials-analysis](#)
- [J.A. Woollam VASE Ellipsometer](#) (Equipment)
 - [equipment](#)
 - [characterization](#)
 - [requires-update](#)
 - [vase-ellipsometer](#)
 - [vase-vb-400](#)
 - [materials-analysis](#)
 - [vase](#)
- [JA Woollam M-2000 Ellipsometer SOP & HA Listing](#) (Equipment)
 - [procedure](#)
 - [in-progress](#)
 - [vase-m2000-ellipsometer](#)
- [VASE Ellipsometer - Controller Upgrade](#) (Equipment)
 - [deployment-log](#)
 - [vase-ellipsometer](#)